PSE-823 Advanced Process Dynamics and Control

Credit Hours:

Pre-requisites: Nil

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Course Objectives:

- To provide an in-depth understanding of process control, with emphasis on the automatic control, which is an essential technology to maintain the safe, economical and environmentally benign operation of manufacturing processes.
- To specifically impasses on realizing the need and challenges for efficient control of complex and highly integrated processes in modern industrial plants.

Course Contents:

- Modeling for Process Dynamics:
 Modeling Tools for Process Dynamics, Inversion by Partial Fractions
- Linear Open-Loop Systems and Closed-Loop Systems: Second Order and Transportation Lag, The Control System, Controllers and Final Control Elements, Block Diagram of a Chemical-Reactor Control System, Proportional Control of System with Measurement Lag, Stability
- Frequency Response: Control System Design by Frequency Response
- State-Space Methods:
 State-Space Representation of Physical Systems, Transfer Function Multivariable
 Control
- Nonlinear Control: Case-studies of Nonlinear Systems, Case-studies of Phase-Plane Analysis
- Process Applications: Advanced Control Strategies, Controller Tuning and Process Identification, Theoretical Analysis of Complex Processes
- Computers in Process Control: Microprocessor-Based Controllers and Distributed Control, Distributed Control

Course Outcomes:

- This course will fill the gap between basic control configurations (Practical Process Control) and model predictive control (MPC).
- In addition, the economic aspects of the application of the various advanced control technologies are stressed throughout this course.

Recommended Reading (including Textbooks and Reference books)

- Smith, Cecil L. Advanced Process Control: Beyond Single Loop Control. John Wiley & Sons, 2011.
- LeBlanc, Steven E., and Donald R. Coughanowr. "Process systems analysis and control." (No Title) (2009).
- Roffel, Brian, and Ben H. Betlem. Advanced practical process control. Berlin, Germany: Springer, 2004.